

Search Notes



Application/Control No.

09/925,259

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

ADAMS ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	9/05	DN
	6		
	7		
	8		
	26		
703	1		
	6		
706	46		
	45		
707	6		
	3		
	223		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US Patent	9/05	DN
US PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
4. IBM-TDB		
5. Derwent		